

Substitute for form 1449A/PTO  <b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b> <i>(Use as many sheets as necessary)</i>	<i>Complete if Known</i>	
	<b>Application Number</b>	10/626,031
	<b>Filing Date</b>	July 23, 2003
	<b>First Named Inventor</b>	Kenneth S. McElvain
	<b>Group Art Unit</b>	2823
	<b>Examiner Name</b>	Clark, Sheila V.
	<b>Attorney Docket No</b>	02986.P028
Sheet 1 of 2		

US PATENT DOCUMENTS					
Examiner Initial *	Cite No <sup>1</sup>	USP Document Number	Publication or Issue Date MM-DD-YYYY	Name of Patentee or Applicant of cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		5,075,753	12/24/1991	Kozono	
		5,288,949	02/22/1994	Crafts	
		5,999,440	12/07/1999	Crafts	
		6,278,148	08/21/2001	Watanabe et al.	
		6,353,189	03/05/2002	Shimada et al.	
		6,388,200	05/14/2002	Schaper	
		6,483,374	11/19/2002	Mizuno et al.	
		6,510,545	01/21/2003	Yee et al.	
		6,603,165	08/05/2003	Yamauchi et al.	
		7,166,352	01/23/2007	Watanabe et al.	
		7,217,887	05/15/2007	Ho	
		7,436,008	10/14/2008	Ho	
		2003/0155642	08/21/2003	Davis et al.	

FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No <sup>1</sup>	Foreign Patent Document Country Code/Number/Kind Code (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T <sup>2</sup>
	1	EP 1497864 B1	06/25/2008	Synplicity, Inc.		
	2	JP 01-152642	06/15/1989	NEC Corp.		*
	3	JP 11-191611	07/13/1999	Hitachi Ltd.		*
	4	JP 2001-127162	05/11/2001	Matsushita Electric Ind Co Ltd.		*
	5	TW (ROC) I 285953	08/21/2007	Synplicity, Inc.		*
	6	TW 462214	11/01/2001	Mitac International Corporation		*
	7	WO 03/092070 A2	11/06/2003	Synplicity, Inc.		
	8	WO 03/092070 A3	11/06/2003	Synplicity, Inc.		

\* only Abstract in English

OTHER DOCUMENTS – NON PATENT LITERATURE DOCUMENTS					
Examiner Initials*	Cite No <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.			T <sup>2</sup>
	9	Banerjee et al., "Analysis and Optimization of Thermal Issues in High-Performance VLSI," ACM, 2001, pages 230-237.			
	10	Hebrard et al., "Design Automation of Power Integrated Circuit in Edge Environment," 1992, IEEE, pages 252-256.			
	11	PCT International Preliminary Report on Patentability for PCT International Application No. US02/24267, mailed April 27, 2006, (4 pages).			
	12	PCT International Search Report for PCT International Application No. US02/24267, mailed May 10, 2004, (8 pages).			
	13	PCT Written Opinion for International Application No. US02/24267, mailed June 23, 2005, (4 pages).			
	14	PCT Written Opinion for International Application No. US03/23559, mailed April 30, 2008, (5 pages).			
	15	Yu et al., "Fast Placement-Dependent Full Chip Thermal Simulation," 2001, IEEE, pages 249-252.			

EXAMINER

DATE CONSIDERED